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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Alexandria, VA.22313, on <u>June</u>2 5 2004. The applicant and/or attorney requests the date of deposit as the filing date. Depositor: Karen Cinq-Mars

(Signature & date)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

e application of

June 25 2004

Chidambarrao Dureseti et al.:

Group Art Unit: 2822

Serial No.10/605,167 :

Examiner: Lazena Martin

Filed: 9/12/2003

International Business Machines Corporation

2070 Route 52

Hopewell Junction, NY 12533

TITLE:

Mosfet Performance Improvement Using Deformation in SOI Structure

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the non-US patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or nonpertinency of the art, that better art than that listed is not available, or that other art is not applicable.

No fee is believed to be due for this submission. If any fees are required, however, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 09-0458.

Respectfully submitted, Chidambarrao Dureseti et al.

Joseph P. Abate, Attorney Registration No. 30,238

Telephone No. 845-894-4633

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FORM PTO-1449 (Modified)  LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)			ATTY. DOCKET NO. SERIAL NO. FIS920030185US1 10/605/167				
LIST OF PAT APPLICANT'S STATEMENT	ENTS AND PUBLICAT S INFORMATION DISC	CLOSUS FOR	APPLICANT: Dureseti Chidambarrao,	et al.			
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REFERENCE I	DESIGNATION	U.S. PA	FENT DOCUMENTS			-	
EXAMINER	DOCUMENT					FILING DATE	
INITIALS	NUMBER	DATE	NAME	CLASS	S SUBCLASS		
	6,228,694 B1	5/8/2001	Doyle et al.				
	6,406,973 B1	6/18/2002	Lee				
	6,281,532 B1	8/28/2001	Doyle et al.				
	5,683,934	11/4/97	Candelaria				
	6,368,931 B1	4/9/2002	Kuhn, et al.				
	5,310,446	5/10/94	Konishi et al.				
	4,853,076	8/1/89	Tsaur et al.				
	US 2002/0090791 A1	7/11/2002	Doyle et al.				
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	6,509,618 B2	7/21/2003	Jan et al.				
	6,476,462 B2	11/5/2002	Shimizu et al.				
	6,362,082 B1	3/26/2002	Doyle et al.			_	
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	5,565,697	10/15/96	Asakawa et al.				
	US 2003/0040158 A1	2/27/2003	Saitoh				
	US 2002/0086472 A1	7/4/2002	Roberds et al.				
	6,521,964 B1	2/18/2003	Jan et al.				
	6,506,652	01/14/03	Jan, et al.				
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	5,081,513	1/14/1992	Jackson, et al.							
	3,602,841	8/31/1971	McGroddy							
	6,531,740	3/11/2003	Bosco, et al.							
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	6,255,169	7/3/2001	Li, et al.							
	6,246,095	6/12/2001	Brady, et al.							
	6,165,383	12/26/2000	Chou							
	6,133,071	10/17/2000	Nagai	<u> </u>						
	6,046,464	4/4/2000	Schetzina							
	6,025,280	2/15/2000	Brady, et al.							
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	5,940,736	8/17/1999	Brady, et al.					
-	5,880,040	3/9/1999	Sun, et al.					
	5,861,651	1/19/1999	Brasen, et al.			<del>                                     </del>		
	5,679,965	10/21/1997	Schetzina					
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	5,561,302	10/1/1996	Candelaria					
	5,471,948	12/5/1995	Burroughes, et al.		_		····	
	5,459,346	10/17/1995	Asakawa, et al.					
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	5,371,399	12/6/1994	Burroughes, et al.					
	5,108,843	4/28/1992	Ohtaka, et al.			-		
	5,060,030	10/22/1991	Hoke				. <u> </u>	
	4,958,213	9/18/1990	Eklund, et al.					
	4,665,415	5/12/1987	Esaki, et al.					
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	5,989,978	11/23/1999	Peidous							
	6,284,626	9/4/2001	Kim							
	6,274,444	8/14/2001	Wang							
	6,261,964	7/17/2001	Wu, et al.							
	6,221,735	4/24/2001	Manley, et al.							
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	6,090,684	7/18/2000	Ishitsuka, et al.							
	6,066,545	5/23/2000	Doshi, et al.							
	6,008,126	12/28/1999	Leedy							
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	5,592,007	1/7/1997	Leedy							
	5,571,741	11/5/1996	Leedy							
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	5,557,122	9/17/1996	Shrivastava, et al.						
	5,354,695	10/11/1994	Leedy						
	5,134,085	7/28/1992	Gilgen, et al.						
	5,006,913	4/9/1991	Sugahara, et al.						
	4,952,524	8/28/1990	Lee, et al.						
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